

Search Notes

Application/Control No.

10/612,766

Examiner

Luan K. Bui

Applicant(s)/Patent under
Reexamination

YEWDALL ET AL.

Art Unit

3728

SEARCHED

Class	Subclass	Date	Examiner
206	438-441	12/19/2005	LKB
	560, 565		
220	216, 326		
	221-227		
	788,795		
	202		
	203.01		
602	41, 48		
	54		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR